



# VertaBond™

High-Volume Automated Vacuum Anneal System  
for WtW Hybrid Bonding, DtP & PtP Bonding



The YES VertaBond™ is a production-proven automated vacuum anneal system equipped with uniform temperature control and laminar gas flow. This system has an EFEM integrated with two process modules that can accommodate 200 mm and 300 mm wafers, or panel sizes ranging from 400 mm to 550 mm. The VertaBond wafer systems can process batch sizes of 50 wafers (one PM) or 100 wafers (two PMs). VertaBond panel systems can process batch sizes of 12 panels (one PM) or 24 panels (two PMs).

## The Vacuum Cure Advantage

- Void-free hybrid bonding in less time and at lower temperatures using vacuum
- Vacuum anneal provides Cu-Cu bonding without voids, delamination or dishing
- Laminar flow reduces/eliminates particles
- Bonding strength increases 3-4.5x under vacuum at temperatures as low as 200°C or 300°C compared to atmospheric anneal
- Vacuum anneal enables 6 µm pitch with no voids or bubbles
- Less film stress and low wafer warpage

## COMMON APPLICATIONS

- 3D packaging
- CMOS image sensors under panel
- Polyimide bake
- Copper anneal
- Wafer to wafer bonding anneal
- DtP and PtP bonding

**Contact Us:** We offer process demonstrations. If you would like to submit samples, please call us. We can run your samples and provide a detailed process report.

**Yield Engineering Systems, Inc.**

Call: **1-510-954-6889** (worldwide) or **1-888-YES-3637** (US toll free)

[www.yieldengineering.com](http://www.yieldengineering.com)



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## 300 MM SYSTEM SPECIFICATIONS

	DESCRIPTION	SPECIFICATION	
SYSTEM / PROCESS	Environment Cleanliness	Class 1 (ISO 3)	
	EFEM Cleanliness	Class 1 (ISO 3)	
	Max Temp	450°C	
	WiW Temp Uniformity	≥ 250°C ± 2.5°C at dwell after temperature stabilization ≤ 250°C ± 1.5°C at dwell after temperature stabilization	
	WtW Temp Uniformity	± 2.5°C at dwell after temperature stabilization	
	Ramp-rate	Maximum 8.0°C/min from 150°C to 350°C (slope)	
	Ramp-down	Maximum 4.0°C/min from 350°C to 150°C (slope)	
	Up-time	≥ 95%	
	MTRR	≤ 4 hours	
	Warpage	≤ 3 mm one side	
	Process Pressure	Sub-atmospheric and atmospheric pressures	
	Process Recipe	YES BKM recipe: one-step process	
	System Footprint	6.5 m <sup>2</sup> (EFEM and one process module); 10.7 m <sup>2</sup> (EFEM and two process modules)	
	HARDWARE	Wafer Size	300 mm
Load Port Quantity		2 or 4	
Process Gas Type		N <sub>2</sub> gas (preheated) - Process grade N <sub>2</sub> preferred	
MFC		N <sub>2</sub> calibrated MFC	
N <sub>2</sub> Flow		20 - 200 SLM	
Pump		Purchasable option (process-dependent)	
Standard Cooling		Forced air cooling outside of chamber	
Pump Exhaust		Scrubber-max flow 21 CFM (provided by customer)	
Aligner		Purchasable option	
Safety Compliance		SEMI S2 and S8, CE and NFPA79 compliance	
Chamber Material		Stainless steel chamber 316L	
Process Capability		One process module for 50 wafers, Two process modules for 100 wafers	
O <sub>2</sub> Concentration		<10 ppm	
Warranty		12 months after acceptance	
SOFTWARE		SEMI Equipment Communication Standard 2 Message Content (SECS II)	SEMI E5
		Generic Model for Communications and Control of SEMI Equipment (GEM)	SEMI E30
		High-Speed SECS Message Services Generic Services (HSMS)	SEMI E37
		High-Speed SECS Message Services Single-Session Mode (HSMS-SS)	SEMI E37.1
	Standard for Carrier Management (CMS)	SEMI E87	
	Specification for Enhanced Carrier Handoff Parallel I/O Interface	SEMI E84	
	Specification for Substrate Tracking (STS)	SEMI E90	
	Specification for Process Job Management (PJM)	SEMI E40	
	Specification for Control Job Management (CJM)	SEMI E94	
	Operating System	Windows 10	

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	WtW Temp Uniformity	± 2.5°C at dwell after temperature stabilization
	Ramp-rate	Maximum 4.0°C/min from 100°C to 350°C (slope)
	Ramp-down	Maximum 3.0°C/min from 350°C to 100°C (slope)
	Up-time	≥ 95%
	MTRR	≤ 4 hours
	Warpage	≤ 3 mm one side
	Process Pressure	Sub-atmospheric and atmospheric pressures
	Process Recipe	YES BKM recipe: one-step process
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Process Gas Type		N <sub>2</sub> gas (preheated) - Process grade N <sub>2</sub> preferred
MFC		N <sub>2</sub> calibrated MFC
N <sub>2</sub> Flow		50 - 200 SLM
Pump		Purchasable option (process-dependent)
Standard Cooling		Forced air cooling outside of chamber
Pump Exhaust		Scrubber-max flow 21 CFM (provided by customer)
Aligner		Purchasable option
Safety Compliance		SEMI S2 and S8 compliance
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